

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/744,746 FUJIMOTO ET AL.	
		Examiner	Art Unit	Page 1 of 1 Cheukfan Lee 2622

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,222,581	04-2001	Fujimoto et al.	347/256
	B	US-6,469,808	10-2002	Onishi et al.	358/475
	C	US-6,448,995	09-2002	Fujimoto et al.	347/241
	D	US-6,166,832	12-2000	Fujimoto, Hisayoshi	358/484
	E	US-5,859,421	01-1999	Onishi et al.	250/208.1
	F	US-6,014,231	01-2000	Sawase et al.	358/482
	G	US-5,579,114	11-1996	Imamura, Masaya	358/482
	H	US-6,295,141	09-2001	Ogura et al.	358/475
	I	US-5,780,840	07-1998	Lee et al.	250/208.1
	J	US-5,570,122	10-1996	Imamura et al.	347/171
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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